Approved for use through 07/31/2008, OMB 0651-0031 U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

rmation unless it displays a valid OMB control number. 10/792,323 **Application Number** ostitute for form 1449A/PTO Filing Date March 3, 2004 First Named Inventor SUPPLEMENTAL INFORMATION Lawrence C. Lei DISCLOSURE STATEMENT BY **Group Art Unit** 1734 **APPLICANT Examiner Name** Sharon Latimer Attorney Docket Number AMAT/5191.C1/ISM/CORE/MCVD/PJS (Use as many sheets as necessary) Sheet of **Submission Date** December 30, 2004

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			U.S. PATENT	DOCUMENTS			
Examiner	Examiner Cite Initials* No.1	Document Number	Publication Date	ate Name of Patentee or	Pages, Columns, Lines, Where		
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Examiner		Foreign Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines,	T <sub>Q</sub>		
Initials* No.1	Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear				
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Examiner	5.	Pate Considered 6/2 a/ov	

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0-	for for 1449A/PTO			Application Number	10/792,323
JUN 14	2004 윤			Filing Date	March 3, 2004
SUPF	PLEEDENTAL INF	ORMA <sup>*</sup>	TION	First Named Inventor	Lawrence C. Lei
DISCLOSURE STATEMENT BY  APPLICANT				Group Art Unit	Unknown
MOLL	APPLICAN'	T		Examiner Name	Unknown
	(Use as many sheets as n	ecessary)		Attorney Docket Number	AMAT/5191.C1/ISM/CORE/MCVD/PJS
Sheet	1	of	11	Submission Date	June 8, 2004

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Subsultite	for form 1449A/PTO			Application Number Filing Date	10/792,323 March 3, 2004
	PLEMENTAL INFOR			First Named Inventor	Lawrence C. Lei
DISC	DISCLOSURE STATEMENT BY			Group Art Unit	Unknown
	APPLICANT			Examiner Name	Unknown
	(Use as many sheets as neces	sary)		Attorney Docket Number	AMAT/5191.C1/ISM/CORE/MCVD/PJS
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June 8, 2004

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of Information unless it displays a valid OMB control number. 10/792,323 Substitute for form 1449A/PTO **Application Number** Filing Date March 3, 2004 SUPPLEMENTAL INFORMATION First Named Inventor Lawrence C. Lei **DISCLOSURE STATEMENT BY Group Art Unit** Unknown **APPLICANT** Unknown **Examiner Name** AMAT/5191.C1/ISM/CORE/MCVD/PJS (Use as many sheets as necessary) Attorney Docket Number

**Submission Date** 

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Initials*	No.'	Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (il known)	MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear		
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Substitut	e for form 1449A/PTO			Application Number	10/792,323
				Filing Date	March 3, 2004
SUP	SUPPLEMENTAL INFORMATION		TION	First Named Inventor	Lawrence C. Lei
DIS	CLOSURE STATE		BY	Group Art Unit	Unknown
	APPLICANT			Examiner Name	Unknown
	(Use as many sheets as ne	cessary)		Attorney Docket Number	AMAT/5191.C1/ISM/CORE/MCVD/PJS
Sheet	4	of	11	Submission Date	June 8, 2004

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				Filing Date	March 3, 2004
	PLEMENTAL INFO			First Named Inventor	Lawrence C. Lei
DISC	CLOSURE STATE	MENT	ВҮ	Group Art Unit	Unknown
	APPLICANT			Examiner Name	Unknown
	(Use as many sheets as nec	cessary)		Attorney Docket Number	AMAT/5191.C1/ISM/CORE/MCVD/PJS
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Examiner	Cite	Foreign Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines,	T <sup>6</sup>	
Initials*	No. <sup>L</sup>	Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear		
У	B26	WO 01/29280 A1	04/26/2001	ASM AMERICA, INC.			
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Examiner ) Date Considered (14/07

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PTO/SB/08a (08-03)

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DISC	PLEMENTAL INFO CLOSURE STATE APPLICANT (Use as many sheets as ne	MENT		First Named Inventor Group Art Unit Examiner Name Attorney Docket Number	Lawrence C. Lei Unknown Unknown AMAT/5191.C1/ISM/CORE/MCVD/PJS
Sheet		of	11	Submission Date	June 8, 2004

			U.S. PATENT	DOCUMENTS			
Examiner	Cite	Document Number	Publication Date	Name of Patentee or	Pages, Column, Lines, Where Relevant Passages or Relevant CUP Figures Appear		
Initials*	No.1	Number-Kind Code <sup>2 (I trown)</sup>	MM-DD-YYYY	Applicant of Cited Document			
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Examiner	Cite	Foreign Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines,	T⁰				
Initials*	No.¹	Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	MM-DD-YYYY Applicant of Cited Document		Where Relevant Passages or Relevant Figures Appear					
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to a collection of information unless it displays a valid OMB control number,

Substitute	for form 1449A/PTO			Application Number	10/792,323
•				Filing Date	March 3, 2004
	LEMENTAL INFO			First Named Inventor	Lawrence C. Lei
DISC	DISCLOSURE STATEMENT BY			Group Art Unit	Unknown
	APPLICANT			Examiner Name	Unknown
	(Use as many sheets as necessary)			Attorney Docket Number	AMAT/5191.C1/ISM/CORE/MCVD/PJS
Sheet	8	of	11	Submission Date	June 8, 2004

			U.S. PATENT	DOCUMENTS			
Examiner	Cite No.1	Document Number	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where		
nitials*	NO.	Number-Kind Code <sup>2 (* krown)</sup>	MM-DD-YYYY	Applicant of Cited Document	Relevant Passages or Relevant		
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Examiner	Cite	Foreign Patent Document	Publication Date	Name of Patentee or Pages, Columns, Lines,		Т°			
Initials* No.1	Country Code <sup>3</sup> -Number Code <sup>3</sup> (il known)	MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear					
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Examiner **Date Considered** 

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PTQ/SB/08a (08-03)

	Under the Papers	YORK MEDUC	HOR ACTOR 1995, N	o persons are required to respond to a collec	tion of unformation unless it displays a valid QMB control number
Substitute	e for form 1449A/PTO			Application Number	10/792,323
				Filing Date	March 3, 2004
	PLEMENTAL INFO			First Named Inventor	Lawrence C. Lei
DIS	DISCLOSURE STATEMENT BY		Group Art Unit	Unknown	
	APPLICANT			Examiner Name	Unknown
	(Use as many sheets as necessary)			Attorney Docket Number	AMAT/5191.C1/ISM/CORE/MCVD/PJS
Sheet	9	of	11	Submission Date	June 8, 2004

			U.S. PATENT	DOCUMENTS		
Examiner Initials*	Cite No.1	Document Number  Number-Kind Code <sup>2 (7 known)</sup>	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Relevant Pass	ages or Relevant
sQ	A146	US-5835677	11/10/1998	LI, ET AL.	Document Helevant Passages of Helevant Figures Appear S V	1
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Examiner	S. X	? <	Date Considered	6/20/05

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Substitute	for form 1449A/PTO			Application Number	10/792,323
				Filing Date	March 3, 2004
SUP	PLEMENTAL IN	FORMA <sup>*</sup>	TION	First Named Inventor	Lawrence C. Lei
DISC	DISCLOSURE STATEMENT BY			Group Art Unit	Unknown
	APPLICAN	NT.	•	Examiner Name	Unknown
	(Use as many sheets as necessary)			Attorney Docket Number	AMAT/5191.C1/ISM/CORE/MCVD/PJS
Sheet	10	of	11	Submission Date	June 8, 2004

			U.S. PATENT	DOCUMENTS	1		
Examiner	Cite	Document Number	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where		
Initials*	No.1	Number-Kind Code <sup>2 (1 known)</sup>	MM-DD-YYYY	Applicant of Cited Document	Relevant Passages o	r Relevant ar ) t- (	
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Examiner	Cite	Foreign Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines,	T⁰				
Initials*	No.1	Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear					
	B46									
	B47									
	B48	***								
	B49									
	B50									

Examiner	5. ?	 Date Considered	6/2/0-

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Under the Paperwork Reduction Act of 1995, no Substitute for form 1449B/PTO				Application Number	10/792,323	
Substitute for form 144507 10				Filing Date	March 3, 2004	
SUPPLEMENTAL INFORMATION				First Named Inventor	Lawrence C. Lei	
DISCLOSURE STATEMENT BY			BY	Group Art Unit	Unknown	
APPLICANT				Examiner Name	Unknown	
(Use as many sheets as necessary)				Attorney Docket Number	AMAT/5191.C1/ISM/CORE/MCVD/PJS	
Sheet	11	of	11	Submission Date	June 8, 2004	

Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published  Kukli, et al., "Tailoring the Dielectric Properties of HfO <sub>2</sub> -Ta <sub>2</sub> -O <sub>5</sub> Nanolaminates," Applied Physics Letters, Vol. 68, No. 26, June 24, 1996; p. 3737-9	۲²
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